Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/506,309	YAMANO ET AL.	
Examiner	Art Unit	_
Andrew B. Freistein	1626	

SEARCHED				
Class	Subclass	Date	Examine	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
546	340	3-19-06	MIF		
548	341.5	3-18-06	ABF		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Restriction	8/15/2005	ABF		
STN (see attached)	11/4/2005	ABF		
STN (see attached)	11/7/2005	ABF		
STIC (see attached)	11/3/2005	ABF		
STIC Inventor Name	11/3/2005	ABF		
EDan Inventor Name	11/7/2005	ABF		
Updated.	3/18/06	MBF		